

EMISSION -- TEST REPORT

TEST REPORT No.:

TR6-09229F

Date of Issue: March 23, 2009

KIND OF EQUIPMENT:

Embedded RFID Read/Write System

MODEL:

4399022A

APPLICANT:

Oki Data Corporation

FCC ID:

B2K-4399022A

TEST STANDARD(S):

FCC Part 15 Subpart C, Section 15.225

TEST RESULT:

Complied

It is not allowed to copy this report even partly without the written allowance of the test laboratory. The test result only responds to the tested sample. The report must not be used to claim products endorsement by the accreditation or authorization body. The engineers of EMC Kashima Corporation were not involved in modification for the tested sample.

TEST DATE(S):

February 25, 26, 2009

TEST ENGINEER(S):

Kazuhiro Ando
ManagerTadashi Kuroda
Assistant Manager

APPROVED BY:

Ken'ichi Suda
Director

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1 GENERAL INFORMATION

1.1	APPLICANT	Oki Data Corporation
1.2	ADDRESS	3-1, Futaba-cho, Takasaki-shi, Gunma-ken 370-8585, Japan
1.3	MANUFACTURER	Oki Data Corporation
1.4	KIND OF EQUIPMENT	Embedded RFID Read/Write System
1.5	MODEL	4399022A
1.6	POWER RATING	DC 5V 0.2W
1.7	TESTING VOLTAGE	DC 5V (AC120V, 60Hz for Printer)
1.8	CONDITION OF EUT	Prototype
1.9	OPERATING FREQUENCY	13.56MHz
1.10	TYPE OF MODURATION	ASK
1.11	OPERATING TEMPERATUR	10 °C to 32 °C
1.12	TEST STANDARD(S)	FCC Part 15 Subpart C, Section 15.225
1.13	TEST METHOD(S)	ANSI C63.4: 2003
1.14	TESTED DATE(S)	February 25, 26, 2009
1.15	REMARK(S)	

2 SUMMARY OF TEST RESULT

FCC Part 15 Section	Test Item	Worst margin	Condition	Result
15.203	Antenna requirement	-	-	Pass ^{Note1}
15.207	Conducted emissions 9kHz - 30MHz	29.9dB at 27.1200MHz	-	Pass
15.225(a)(b)(c)	Radiated emissions 9kHz - 30MHz	88.3dB at 13.56MHz	Radiated	Pass
15.225(d)	Radiated emissions 9kHz - 30MHz	48.3dB at 27.12MHz	Radiated	Pass
15.225(d) 15.209	Radiated emissions 30MHz - 1GHz	11.6dB at 230.52MHz	Radiated	Pass
15.225(e)	Frequency stability	0.0009%	Conducted	Pass
15.215(c)	20dB Bandwidth	6.26kHz	Conducted	Pass

Note 1: Users cannot replace the antenna since it is attached to the inside of the printer.

Note 2: "Pass" is only based on the measurement data and it does not include the measurement uncertainty.

Accordingly, the statement below is applied to the test result.

- It is possible to determine compliance at a level of confidence of 95% in case that the margin is not less than the measurement uncertainty in the Laboratory.
- It is not possible to determine compliance at a level of confidence of 95% in case that the margin is less than the measurement uncertainty in the Laboratory. However, the measured result indicates that the product tested complies with the specification limit.

3 EQUIPMENT UNDER TEST

3.1 Description of The EUT

The RFID equipment we'll make an application is built in a printer and is used for checking remaining amount of the toner.

3.2 Operation - mode of The EUT

The equipment under test was operated during the measurement under following conditions:

- Transmitting and Receiving mode (with Passive Tag)

4 TEST CONFIGURATION

4.1 EUT(s) and Peripheral(s)

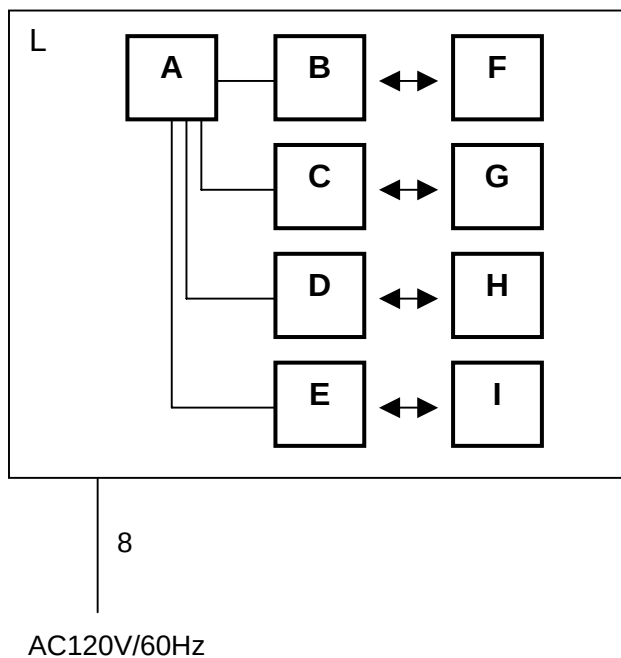
	Equipment Name	Model	Serial No.	Company	FCC ID
A	RFID Module (EUT)	4399022A	1 (for Conducted Emissions) 2 (for Other Emissions)	Oki Data Corporation	B2K-4399022A
B	Antenna Unit (EUT)	-	-	Oki Data Corporation	B2K-4399022A
C	Antenna Unit (EUT)	-	-	Oki Data Corporation	B2K-4399022A
D	Antenna Unit (EUT)	-	-	Oki Data Corporation	B2K-4399022A
E	Antenna Unit (EUT)	-	-	Oki Data Corporation	B2K-4399022A
F	Tag (EUT)	-	-	Oki Data Corporation	B2K-4399022A
G	Tag (EUT)	-	-	Oki Data Corporation	B2K-4399022A
H	Tag (EUT)	-	-	Oki Data Corporation	B2K-4399022A
I	Tag (EUT)	-	-	Oki Data Corporation	B2K-4399022A
J	Micro-Computer for Test	None	None	Oki Data Corporation	N/A
K	DC Power Supply	GSV3000	60646741	Daiichi Denpa	N/A
L	Printer	N31193A	1	Oki Data Corporation	DoC*
*Note: Declaration of Conformity					
N/A: Not Applicable					

4.2 Cable(s) Used

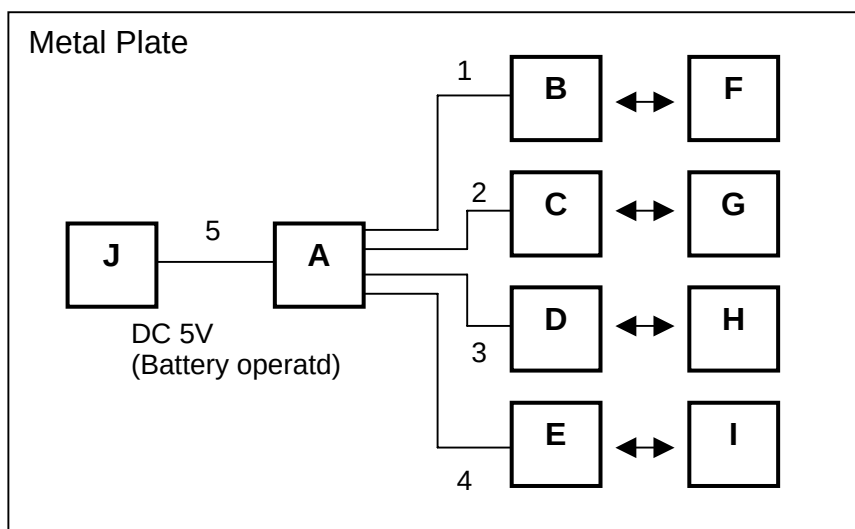
	Cable Name	Length	Shielded	Remarks (Model, Company, etc.)
1	Antenna	0.125 m	no	43171501YS
2	Antenna	0.07 m	no	43171502YS
3	Antenna	0.07 m	no	43171502YS
4	Antenna	0.125 m	no	43171501YS
5	Signal	0.4 m	no	
6	DC Power (EUT)	3.0 m	no	
7	AC Power (DC Power Supply)	1.7 m	no	
8	AC Power (Printer)	1.8 m	no	

4.3 Connection figure

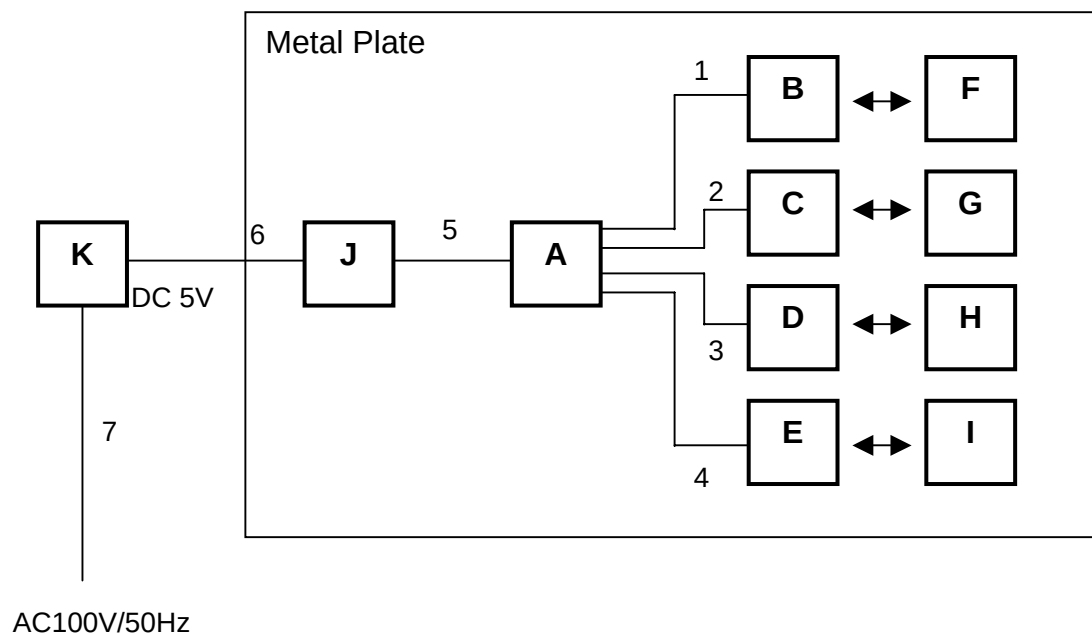
Conducted Emissions



Radiated Emissions



Frequency stability Test condition



5 TEST FACILITIES

All measurement facilities in EMC Kashima Corporation are located in 1614, Mushihata, Katori-shi, Chiba-ken, 289-0341 Japan.

Accredited by American Association for Laboratory Accreditation (A2LA) for the emission and immunity tests stated in the scope of the certificate under Certificate Number 1266-01.

Authorized by TUV Rheinland for the emission and immunity tests stated in the scope of the certificate under Certificate No. UA 50061520-0001.

Registered by Federal Communications Commission (FCC). Each registered facility number is as follows;

Test site No. 1 90558 / Test site No. 2 510504 / Test site No. 4 90557

Test site No. 5 99356 / Test site No. 6 372431

Registered by Industry Canada (IC). Each registered facility number is as follows;

Test site No. 1 IC 4659A-1 / Test site No. 2 IC 4659A-2 / Test site No.5 IC 4659A-5

Test site No. 6 IC 4659A-6

Approved by Saudi Arabian Standards Organization (SASO).

Registered by Voluntary Control Council for Interference by Information Technology Equipment (VCCI).

Each registered facility number is as follows;

Test site No. 1 R-188 · C-785 (Open site) / C-187 (Shielded room)

Test site No. 2 R-189 (Open site) / C-188 (Shielded room)

Test site No. 4 R-656 (Open site) / C-613 (Shielded room)

Test site No. 5 R-1227 · C-1290 (Open site) / C-1291 (Shielded room)

Test site No. 6 R-1895 · C-2042 (Anechoic chamber)

6 MEASUREMENT UNCERTAINTY

The treatment of uncertainty is based on the general matters on the definition of uncertainty in “Guide to the expression of uncertainty in measurement (GUM)” published by ISO. The Lab’s uncertainty is determined by referring UKAS Publication LAB34:2002 “The Expression of Uncertainty in EMC Testing” and CISPR16-4-2:2003 “Uncertainty in EMC Measurements”.

The uncertainty of the measurement result in the level of confidence of approximately 95% (k=2) is as follows;

Conducted Emissions	± 2.56 dB
Radiated emission test (9kHz - 30MHz)	± 3.25 dB
Radiated emission test (30MHz - 1000MHz)	± 4.32 dB

7 TEST CONDITIONS

7.1 Section 15.207 Conducted Emissions

7.1.1 Test Location

Test site No. 6 (Anechoic chamber)

7.1.2 Used Test Instruments

Model	Name	Manufacturer	Code No.	Last Cal.	Remarks
ESCI	Test Receiver	Rohde & Schwarz	RCV06	2008.10	
ESH3-Z5	AMN	Rohde & Schwarz	LSN08	2008.07	
8568A	Spectrum Analyzer	Hewlett Packard	SPR04	2008.10	
5D-2W	Coaxial cable	FUJIKURA	6CSAC	2009.01	

All used test instruments are calibrated at least once a year.

7.1.3 Test Procedure

The test setup and measurements were implemented according to the test method of ANSI C63.4: 2003
7. AC power line conducted emission measurements.

Final measurements were made on the conditions described on this page, and the photos of test-setup indicate the final conducted emissions.

7.1.4 Limit

Frequency (MHz)	Quasi-peak (dBuV)	Average (dBuV)
0.15 - 0.5	66 - 56*	56 - 46*
0.5 - 5	56	46
5 - 30	60	50

* Decreases with the logarithm of the frequency.

7.2 Section 15.225(a)(b)(c)(d) Radiated Emissions (9kHz - 30MHz)

7.2.1 Test Location

Test site No. 6 (Anechoic chamber) 3 meters distance

7.2.2 Used Test Instruments

Model	Name	Manufacturer	Code No.	Last Cal.	Remarks
ESHS10	Test Receiver	Rohde & Schwarz	RCH02	2008.03	
HFH2-Z2	Loop Antenna	Rohde & Schwarz	LPA01	2008.04	
5D-2W	Coaxial cable	FUJIKURA	MG5m	2008.05	

All used test instruments are calibrated at least once a year.

7.2.3 Test Procedure

The test setup and measurements were implemented according to the test method of ANSI C63.4: 2003 8. Radiated emission measurements.

The test was performed at 3 meter distance and its result was converted into the one at specified 30 meter distance according to 15.31(f). The turntable was rotated and the center point of the loop antenna was fixed at 1 meter above ground level to investigate the maximum radiated emission, positioning the loop antenna in vertical and horizontal. Final measurements were made on the conditions described on this page, and the photos of test-setup indicate the final radiated emissions.

7.2.4 Limit

Frequency (MHz)	Field strength @30m (uV/m)	Field strength @30m (dBuV/m)	Field strength @3m (dBuV/m)
Below 13.110	30	29.5	69.5
13.110 - 13.410	106	40.5	80.5
13.410 - 13.553	334	50.5	90.5
13.553 - 13.567	15,848	84	124
13.567 - 13.710	334	50.5	90.5
13.710 - 14.010	106	40.5	80.5
Above 14.010	30	29.5	69.5

$\text{dBuV/m} = 20 \times \log(\text{uV/m})$

Distance factor = 40dB / decade (15.31(f))

7.3 Section 15.225(d) Radiated Emissions (30MHz - 1000MHz)

7.3.1 Test Location

Test site No. 6 (Anechoic chamber) 3 meters distance

7.3.2 Used Test Instruments

Model	Name	Manufacturer	Code No.	Last Cal.	Remarks
ESCI	Test Receiver	Rohde & Schwarz	RCV06	2008.10	
LPB-2520/A	Biconi.-Logperi. Ant.	Antenna Research	BL04	2008.04	
8568B	Spectrum Analyzer	Hewlett Packard	SPR04	2008.10	
8447D	Pre-Amplifier	Hewlett Packard	PRA01	2009.01	
RG 214/U	Coaxial cable	SUHNER	6R3m	2009.01	

All used test instruments are calibrated at least once a year.

7.3.3 Test Procedure

The test setup and measurements were implemented according to the test method of ANSI C63.4: 2003 8. Radiated emission measurements.

They were performed at the measurement distance that specified for compliance to determine the frequency producing the maximum emissions. The turntable was rotated and the antenna height was varied 1 to 4 meters to investigate the maximum radiated emission for the horizontal and vertical polarization. Final measurements were made on the conditions described on this page, and the photos of test-setup indicate the final radiated emissions.

7.3.4 Limit

Frequency (MHz)	Field strength @3m (uV/m)	Field strength @3m (dBuV/m)
30 - 88	100	40
88 - 216	150	43.5
216 -960	200	46
Above 960	500	54

$\text{dBuV/m} = 20 \times \log (\text{uV/m})$

7.4 Section 15.225(e) Frequency Stability

7.4.1 Test Location

Test site No. 6

7.4.2 Used Test Instruments

Model	Name	Manufacturer	Code No.	Last Cal.	Remarks
R3162	Spectrum Analyzer	ADVANTEST	SPTG02	2008.05	
8494B	Attenuator	HP	SAT05	2008.10	
8495B	Attenuator	HP	SAT06	2008.10	
Sucoflex 104	Micro Wave cable	SUHNER	MWC-3m	2009.02	
Sucoflex 104	Micro Wave cable	SUHNER	MWC-0.5m	2009.02	
PR-4KPH	Temperature Chamber	ESPEC	TMPC02	2008.12	
112	MULTIMETER	FLUKE	MTM27	2008.10	
GSV3000	DC Power Supply	Daiichi Denpa	DCPS10	2009.01	

All used test instruments are calibrated at least once a year.

7.4.3 Test Procedure

The test setup and measurements were implemented according to the test method of ANSI C63.4: 2003 Annex H5.

The EUT was measured with the condition that the measuring instrument was connected to the antenna through the coaxial cable, whose antenna was placed near the EUT. The measurement started with the Temperature chamber sufficiently stabilized.

7.4.4 Limit

Item	Variation	Limit (%)
Temperature variation	-20°C - +50°C	+/- 0.01
Voltage variation	85% - 115%	+/- 0.01

7.5 Section 15.215(c) 20dB Bandwidth

7.5.1 Test Location

Test site No. 6

7.5.2 Used Test Instruments

Model	Name	Manufacturer	Code No.	Last Cal.	Remarks
R3162	Spectrum Analyzer	ADVANTEST	SPTG02	2008.05	
8494B	Attenuator	HP	SAT05	2008.10	
8495B	Attenuator	HP	SAT06	2008.10	
Sucoflex 104	Micro Wave cable	SUHNER	MWC-3m	2009.02	
Sucoflex 104	Micro Wave cable	SUHNER	MWC-0.5m	2009.02	
PR-4KPH	Temperature Chamber	ESPEC	TMPC02	2008.12	
112	MULTIMETER	FLUKE	MTM27	2008.10	
GSV3000	DC Power Supply	Daiichi Denpa	DCPS10	2009.01	

All used test instruments are calibrated at least once a year.

7.5.3 Test Procedure

The test setup and measurements were implemented according to the test method of ANSI C63.4: 2003 Annex H6.

The spectrum analyzer RBW and VBW were set as follows. The marker-to-peak function of the spectrum analyzer was used to measure to peak level and the marker-delta function was used to measure the emission 20dB below the peak. It has been plotted.

Spectrum Analyzer Setup

RBW	VBW	Detector
1kHz	3kHz	Peak

8 TEST DATA

8.1 Section 15.207 Conducted Emissions

Company : Oki Data Corporation
 Equipment : Embedded RFID Read/Write System
 Model : 4399022A
 Power : DC 5V (AC120V, 60Hz for Printer)
 Test Mode : Transmitting and Receiving mode

Tested Date : February 25, 2009
 Temperature : 21 °C
 Humidity : 41 %
 Atmos. Press : 1008 hPa

Engineer : Tadashi Kuroda

Freq. (MHz)	Phase	Reading (dBuV)		Corr. Factor (dB)	Result (dBuV)		Limit (dBuV)		Margin (dB)	
		QP	AV		QP	AV	QP	AV	QP	AV
0.1500	N	31.0	-	0.1	31.1	-	66.0	56.0	34.9	-
0.2533	N	25.2	-	0.1	25.3	-	61.6	51.6	36.3	-
0.3808	N	22.2	-	0.2	22.4	-	58.3	48.3	35.9	-
0.8898	N	17.6	-	0.2	17.8	-	56.0	46.0	38.2	-
13.5600	N	10.5	-	1.0	11.5	-	60.0	50.0	48.5	-
18.7192	N	21.5	-	1.4	22.9	-	60.0	50.0	37.1	-
27.1200	N	28.5	-	1.6	30.1	-	60.0	50.0	29.9	-
0.1500	L	30.8	-	0.1	30.9	-	66.0	56.0	35.1	-
0.2533	L	29.0	-	0.1	29.1	-	61.6	51.6	32.5	-
0.3808	L	26.2	-	0.2	26.4	-	58.3	48.3	31.9	-
0.8898	L	18.0	-	0.2	18.2	-	56.0	46.0	37.8	-
13.5600	L	12.0	-	1.0	13.0	-	60.0	50.0	47.0	-
18.7192	L	27.0	-	1.4	28.4	-	60.0	50.0	31.6	-
27.1200	L	21.8	-	1.6	23.4	-	60.0	50.0	36.6	-

Correction Factor(dB) = AMN Factor(dB) + Cable Loss(dB)

Result(dBuV) = Reading (dBuV) + Correction Factor(dB)

8.2 Section 15.225(a)(b)(c) Radiated Emissions (9kHz - 30MHz)

Company : Oki Data Corporation Tested Date : February 25, 2009
Equipment : Embedded RFID Read/Write System Temperature : 21 °C
Model : 4399022A Humidity : 41 %
Power : DC 5V Atmos. Press : 1008 hPa
Test Mode : Transmitting and Receiving mode
Test Distance : 3m

Engineer : Tadashi Kuroda

Freq. (MHz)	Reading @3m (dBuV)	Detector (QP/Pk)	Corr. Factor (dB)	Result (dBuV/m)	Limit @3m (dBuV/m)	Margin (dB)
13.5600	35.5	QP	0.2	35.7	124.0	88.3

Correction Factor(dB) = Antenna Factor(dB/m) + Cable Loss(dB)

Result(dBuV/m) = Reading(dBuV) + Correction Factor(dB)

The test examined it with a new battery.

Section 15.225(d) Radiated Emissions (9kHz - 30MHz)

Company : Oki Data Corporation Tested Date : February 25, 2009
Equipment : Embedded RFID Read/Write System Temperature : 21 °C
Model : 4399022A Humidity : 41 %
Power : DC 5V Atmos. Press : 1008 hPa
Test Mode : Transmitting and Receiving mode
Test Distance : 3m

Engineer : Tadashi Kuroda

Freq. (MHz)	Reading @3m (dBuV)	Detector (QP/Pk)	Corr. Factor (dB)	Result (dBuV/m)	Limit @3m (dBuV/m)	Margin (dB)
27.1200	21.0	QP	0.2	21.2	69.5	48.3

Correction Factor(dB) = Antenna Factor(dB/m) + Cable Loss(dB)

Result(dBuV/m) = Reading(dBuV) + Correction Factor(dB)

The test examined it with a new battery.

8.3 Section 15.225(d) Radiated Emissions (30MHz - 1000MHz)

Company : Oki Data Corporation
 Equipment : Embedded RFID Read/Write System
 Model : 4399022A
 Power : DC 5V
 Test Mode : Transmitting and Receiving mode
 Test Distance : 3m

Tested Date : February 26, 2009

Temperature : 22 °C

Humidity : 48 %

Atmos. Press : 1019 hPa

Engineer : Tadashi Kuroda

Freq. (MHz)	Pol. (H/V)	Reading (dBuV)	Detector (QP/Pk)	Corr. Factor (dB)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)
189.83	H	39.1	QP	-15.5	23.6	43.5	19.9
216.96	H	43.0	QP	-14.1	28.9	46.0	17.1
230.52	H	47.5	QP	-13.1	34.4	46.0	11.6
244.07	H	45.5	QP	-12.2	33.3	46.0	12.7
637.31	V	33.1	QP	-5.4	27.7	46.0	18.3
664.43	V	34.2	QP	-5.0	29.2	46.0	16.8
732.23	V	29.6	QP	-3.5	26.1	46.0	19.9
772.91	H	31.0	QP	-2.4	28.6	46.0	17.4
772.91	V	33.1	QP	-2.4	30.7	46.0	15.3
800.03	H	28.0	QP	-1.7	26.3	46.0	19.7
800.03	V	30.0	QP	-1.7	28.3	46.0	17.7

Correction Factor(dB) = Antenna Factor(dB/m) + Cable Loss(dB) – Preamplifier Gain(dB)

Result(dBuV/m) = Reading(dBuV) + Correction Factor(dB)

The test examined it with a new battery.

8.4 Section 15.225(e) Frequency Stability

Company : Oki Data Corporation
 Equipment : Embedded RFID Read/Write System
 Model : 4399022A
 Power : DC 5V
 Test Mode : Transmitting and Receiving mode

Tested Date : February 26, 2009
 Temperature : 22 °C
 Humidity : 48 %
 Atmos. Press : 1019 hPa

Engineer : Kazuhiro Ando

Temperature Variations

Temp. (°C)	Voltage (V)	Measured Frequency (MHz)				Worst Deviation (%)	Limit (%)
		Start-up	2 min.	5 min.	10 min.		
50	5	13.55988	13.55988	13.55988	13.55988	0.0009	+/- 0.01
40	5	13.55991	13.55990	13.55990	13.55990	0.0007	+/- 0.01
30	5	13.55994	13.55994	13.55993	13.55993	0.0005	+/- 0.01
20	5	13.55997	13.55997	13.55997	13.55997	0.0002	+/- 0.01
10	5	13.55999	13.55999	13.55999	13.55999	0.0001	+/- 0.01
0	5	13.56000	13.56000	13.56000	13.56000	0.0000	+/- 0.01
-10	5	13.55998	13.55998	13.55998	13.55998	0.0001	+/- 0.01
-20	5	13.55994	13.55994	13.55994	13.55994	0.0004	+/- 0.01

Voltage Variations

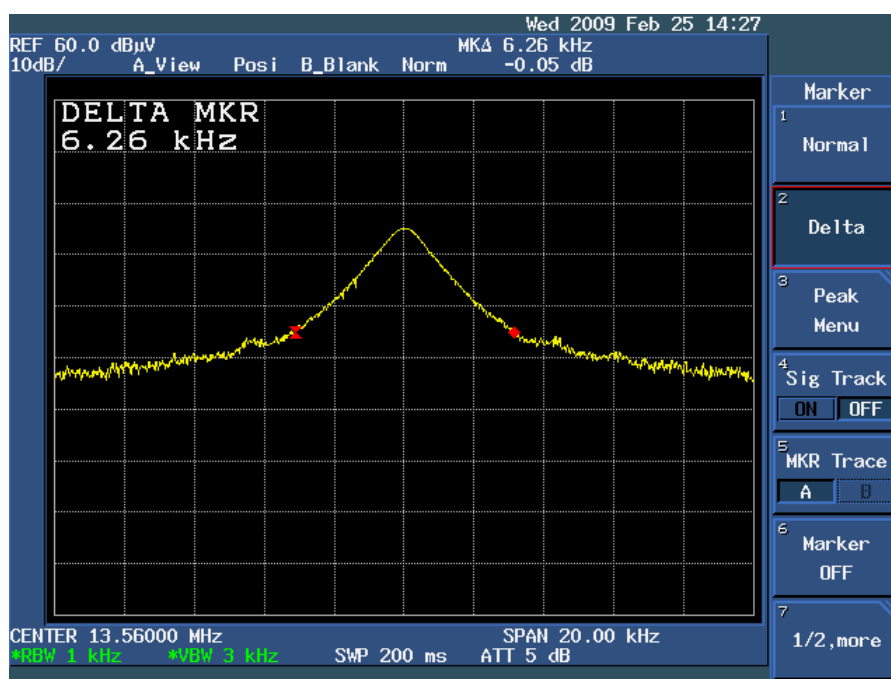
Temp. (°C)	Voltage (V)	Measured Frequency (MHz)				Worst Deviation (%)	Limit (%)
		Start-up	2 min.	5 min.	10 min.		
20	4.25	13.55995	13.55995	13.55995	13.55995	0.0004	+/- 0.01
20	5	13.55997	13.55997	13.55997	13.55997	0.0002	+/- 0.01
20	5.75	13.55999	13.55998	13.55998	13.55998	0.0001	+/- 0.01

8.5 Section 15.215(c) 20dB Bandwidth

Company	: Oki Data Corporation	Tested Date	: February 25, 2009
Equipment	: Embedded RFID Read/Write System	Temperature	: 21 °C
Model	: 4399022A	Humidity	: 43 %
Power	: DC 5V	Atmos. Press	: 1008 hPa
Test Mode	: Transmitting and Receiving mode		

Engineer : Tadashi Kuroda

Freq. (MHz)	20dB Bandwidth (kHz)
13.56	6.26



9 THE PHOTOS OF TEST-SETUP

9.1 Conducted Emissions 150 kHz - 30 MHz



9.2 Radiated Emissions 9 kHz - 1000 MHz



9.3 Frequency Stability

